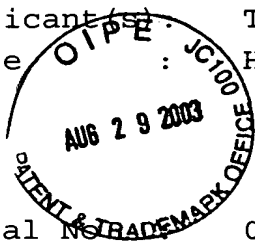


1756

PATENT APPLICATION

Applicant: Toshiaki MOTONAGA et al.

Title: HALFTONE PHASE SHIFTING PHOTOMASK AND BLANKS FOR
HALFTONE PHASE SHIFTING PHOTOMASK THEREFOR AND A
METHOD FOR FORMING PATTERN BY USING THE HALFTONE
PHASE SHIFTING PHOTOMASK



Serial No. 09/825 578

Group: 1756

Confirmation No.: 9940

Filed: April 3, 2001

Examiner: S. Rosasco

International Application No.: N/A

International Filing Date: N/A

Atty. Docket No.: OPS Case 529

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

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SEP 03 2003

TC 1700

FIRST CLASS MAILING CERTIFICATE

Sir:

I hereby certify that this correspondence is being deposited with the United States Postal Service under 37 CFR 1.8 as first class mail in an envelope addressed to: Commissioner for Patents P.O. Box 1450, Alexandria, VA 22313-1450, on August 27, 2003.


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Reg. No. 24 323
Reg. No. 25 072
Reg. No. 22 724
Reg. No. 32 549
Reg. No. 36 589
Reg. No. 31 257
Reg. No. 24 949
Reg. No. 40 694
Reg. No. 36 328
Reg. No. 37 714

Correspondence: Information Disclosure Statement dated
August 27, 2003
Copy of Search Report issued June 25, 2003 in
European Application No. 01108402.7
Form PTO-1449 and one copy of each listed
reference
Postal Card

190.05/03

9/5/03
#9/IDS



PATENT APPLICATION

IN THE U.S. PATENT AND TRADEMARK OFFICE

August 27, 2003

Applicant(s): Toshiaki MOTONAGA et al.

For: HALFTONE PHASE SHIFTING PHOTOMASK AND BLANKS FOR
HALFTONE PHASE SHIFTING PHOTOMASK THEREFOR AND A METHOD
FOR FORMING PATTERN BY USING THE HALFTONE PHASE
SHIFTING PHOTOMASK

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Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(c)(1) and 1.98, enclosed is the Search Report issued in the European application corresponding to the instant application, Form PTO-1449, and the references cited therein.

The undersigned hereby certifies under Rule 1.97(e)(1) that each item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement.

Respectfully submitted,


Liane L. Churney

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Encl: Copy of Search Report issued June 25, 2003 in European
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INFORMATION
DISCLOSURE
CITATION

Applicant: Toshiaki MOTONAGA et al.
 Ser.No. : 09/825 578 Filed : April 3, 2001
 Conf. No.: 9940 Atty.Ref.: OPS Case 529
 Group : 1756

U.S. PATENT DOCUMENTS

Examiner Initial*	Document Number	Date	Name	Class	Sub Class	Filing Date
	AA	5 629 115	05/1997	Kawano et al.		
	AB	5 907 393	05/1999	Kawano et al.		
	AC	5 916 712	06/1999	Miyashita et al.		
	AD	5 938 897	08/1999	Isao et al.		
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Sub Class	Translation Yes No
	AL	JP 09-244212	09/1997	Japan	With English translation and English-language Abstract.	
	AM					
	AN					
	AO					
	AP					

OTHER DOCUMENTS (Including Author, Title, Date, Pages, Etc.)

	AR	
	AS	

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.